

<b>Notice of References Cited</b>	Application/Control No. 10/073,059	Applicant(s)/Patent Under Reexamination THANG ET AL.	
	Examiner Binh Q. Nguyen	Art Unit 2664	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0004843	01-2002	Andersson et al.	709/238
*	B	US-2001/0046227	11-2001	Matsuhira et al.	370/355
*	C	US-6,768,740	07-2004	Perlman et al.	370/392
*	D	US-2002/0101875	08-2002	Lui et al.	370/402
*	E	US-2003/0026268	02-2003	Navas, Julio Cesar	370/400
*	F	US-2002/0029287	03-2002	Yemini et al.	709/238
*	G	US-2002/0186654	12-2002	Tornar, Massimiliano	370/225
*	H	US-6,163,453	12-2000	Hou et al.	361/687
*	I	US-6,154,463	11-2000	Aggarwal et al.	370/408
*	J	US-6,202,082	03-2001	Tomizawa et al.	709/201
*	K	US-6,934,249	08-2005	Bertin et al.	370/218
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.